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# ***ECE 145B / 218B, notes set 4: Methods for Circuit Noise Analysis***

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# References and Citations:

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Sources / Citations :

Kittel and Kroemer : Thermal Physics

Van der Ziel : Noise in Solid - State Devices

Papoulis : Probability and Random Variables (hard, comprehensive)

Peyton Z. Peebles : Probability, Random Variables, Random Signal Principles (introductory)

Wozencraft & Jacobs : Principles of Communications Engineering.

Motchenbaker : Low Noise Electronic Design

Information theory lecture notes : Thomas Cover, Stanford, circa 1982

Probability lecture notes : Martin Hellman, Stanford, circa 1982

National Semiconductor Linear Applications Notes : Noise in circuits.

Suggested references for study.

Van der Ziel, Wozencraft & Jacobs, Peebles, Kittel and Kroemer

Papers by Fukui(device noise), Smith & Personik (optical receiver design)

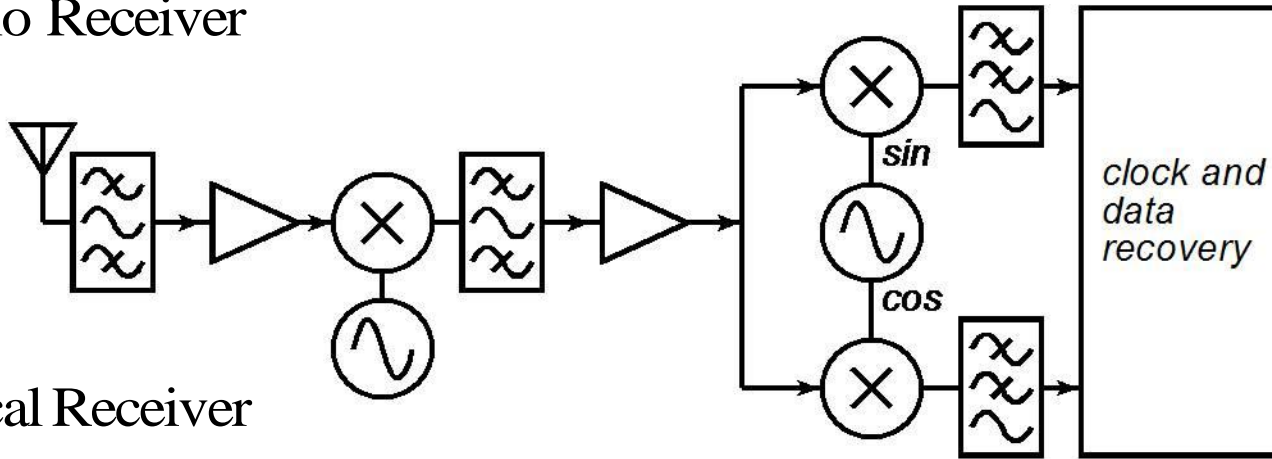
National Semi. App. Notes (!)

Cover and Williams : Elements of Information Theory

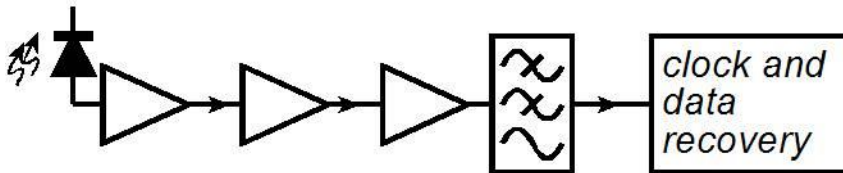
**summary**

# Goal: Computing Signal/Noise Ratio and Sensitivity

Radio Receiver



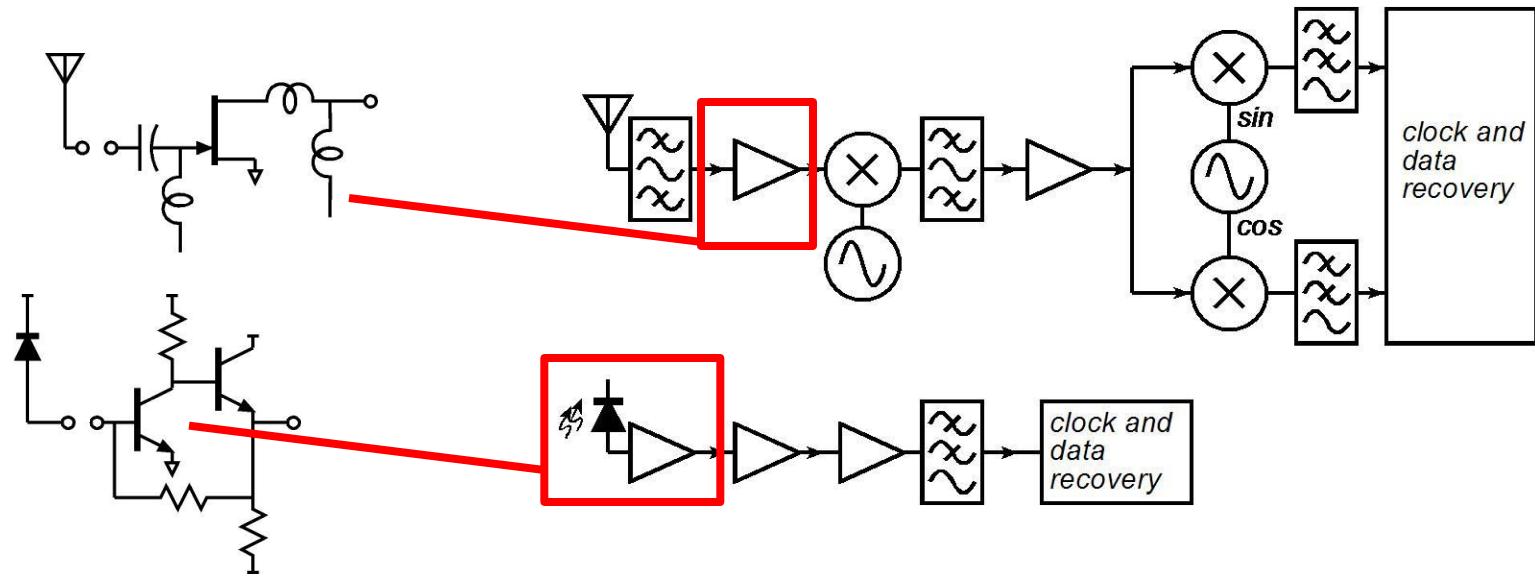
Optical Receiver



To compute the receiver sensitivity,  
we must find the signal/noise ratio at the decision circuit input.

It is often convenient to compare the input signal magnitude  
to the equivalent input-referred noise.

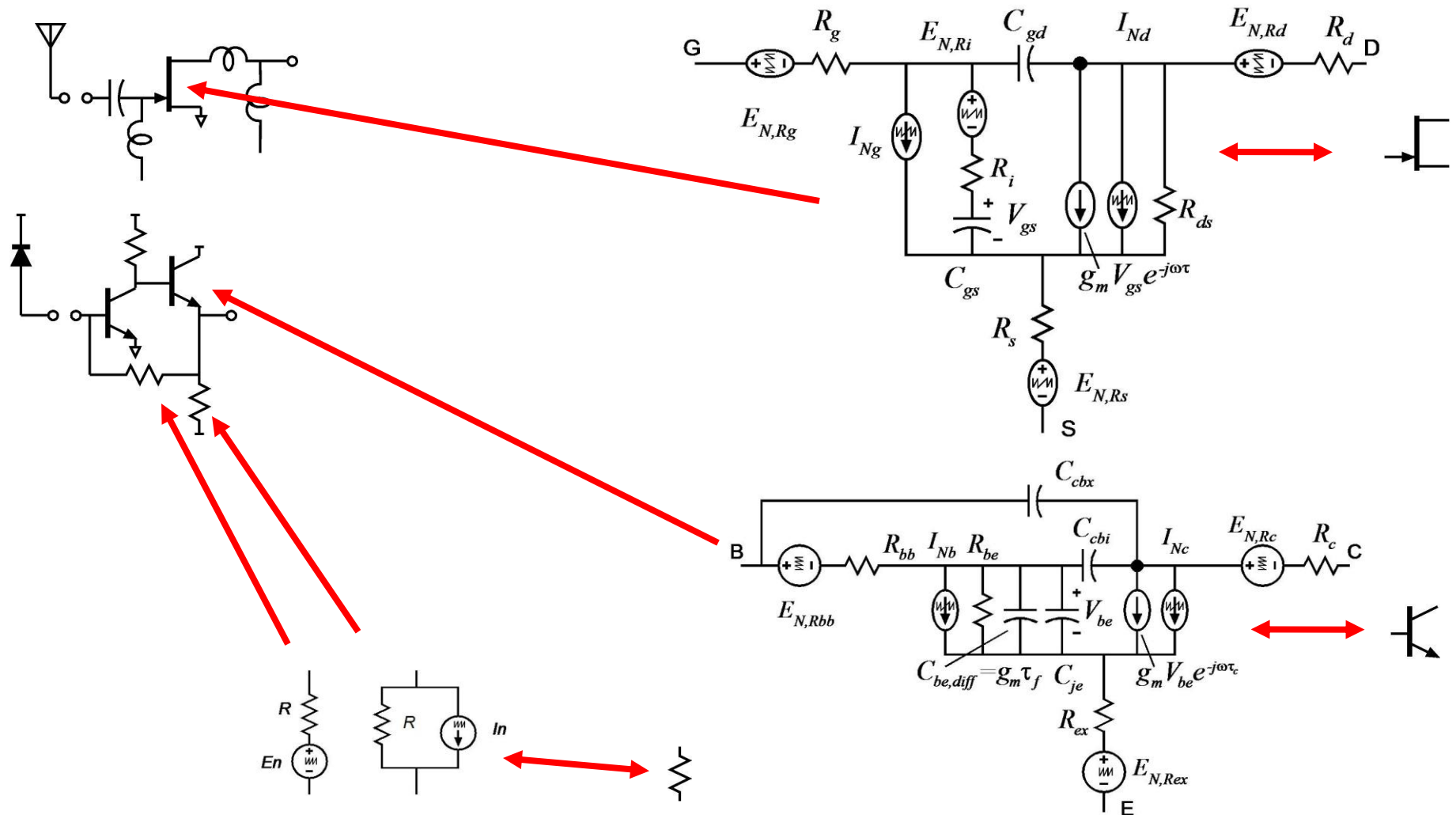
# Goal: Computing Signal/Noise Ratio and Sensitivity



Each functional block of the radio receiver is a subcircuit

Each sub - circuit contains active and passive devices, all having noise models

# Goal: Computing Signal/Noise Ratio and Sensitivity

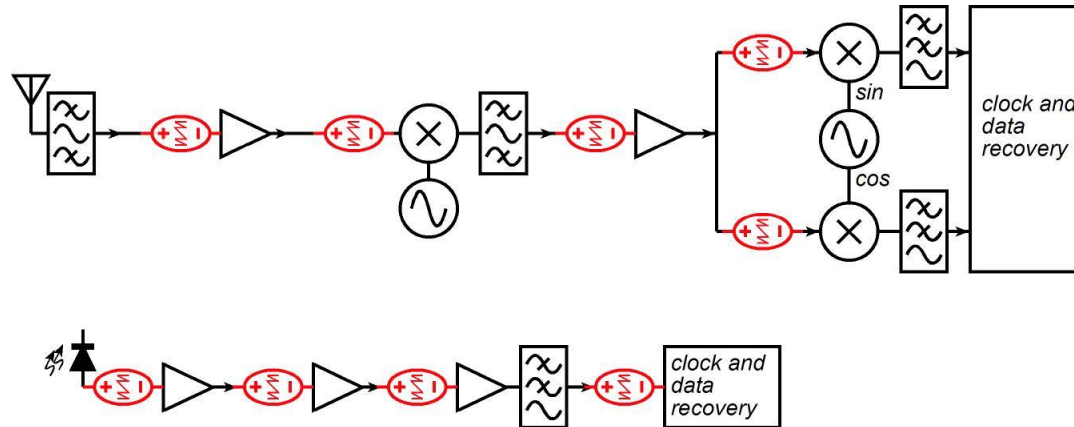


There are a large # of noise generators within each circuit block

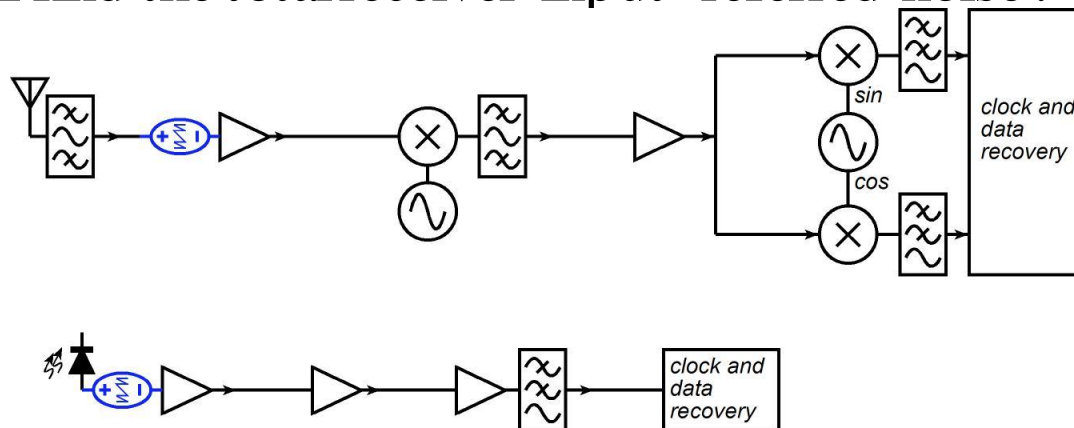
# Goal: Computing Signal/Noise Ratio and Sensitivity

Earlier we found device terminal noise arising from internal fluctuations.

Next we learn to compute the equivalent input noise of each sub-circuit :



From this we will find the total receiver input - referred noise :

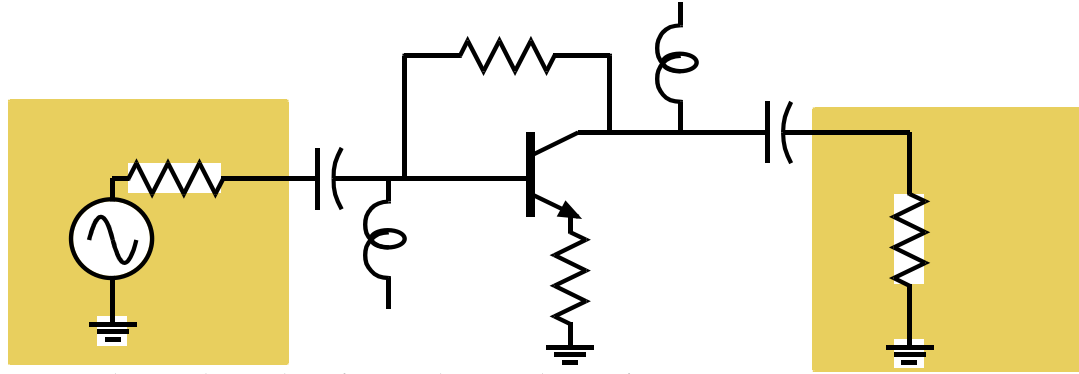


Receiver SNR and sensitivity can then be found.

# **circuit noise calculations**



# Circuit noise analysis: Goals



The circuit output has both signal and noise.

$$V_{out} = A_v V_{in} + V_{noise,output}$$

Noise arises from the generator, the amplifier, and the load

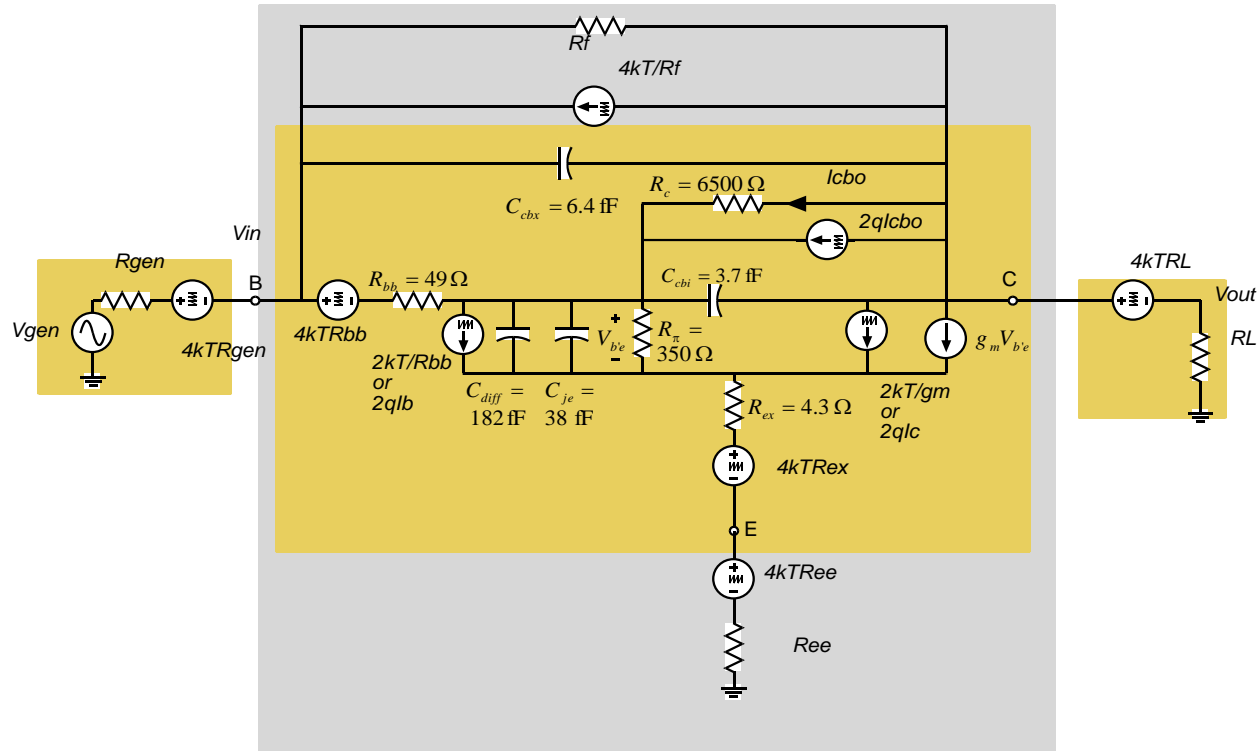
$$V_{noise,output} = V_{noise,generator} + V_{noise,amplifier} + V_{noise,load}$$

These noise terms can be represented by fictitious input terms :

$$V_{out} = A_v V_{in} + V_{noise,output} = A_v (V_{in} + V_{noise,input}), \text{ where } V_{noise,input} = V_{noise,output} / A_v$$

How do we calculate the output-referred noise ?

# Noise model of this circuit



The circuit has a large number of noise generators.

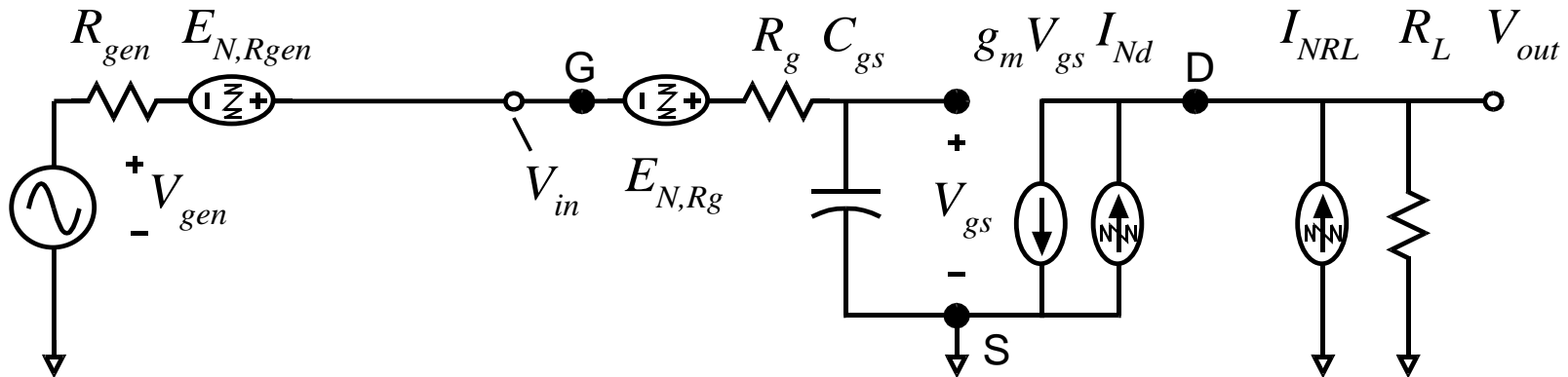
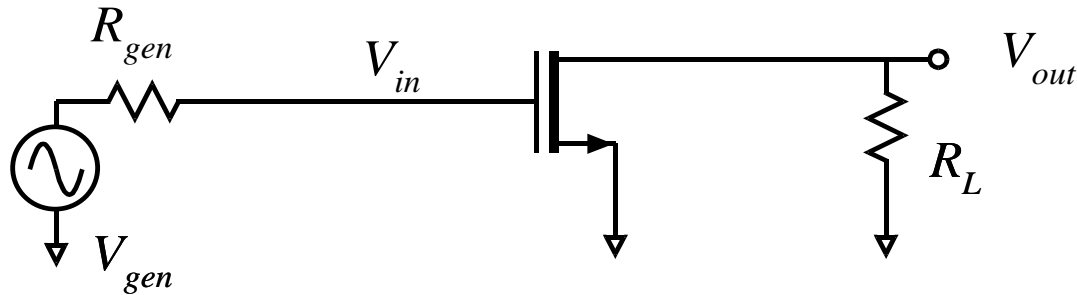
Noise analysis of most practical circuits is of formidable complexity.

Brute-force methods are too hard for hand analysis.

We will learn more efficient techniques.

We will illustrate calculations with a very simple circuit.

# Circuit Noise Analysis: 1st Example (a)



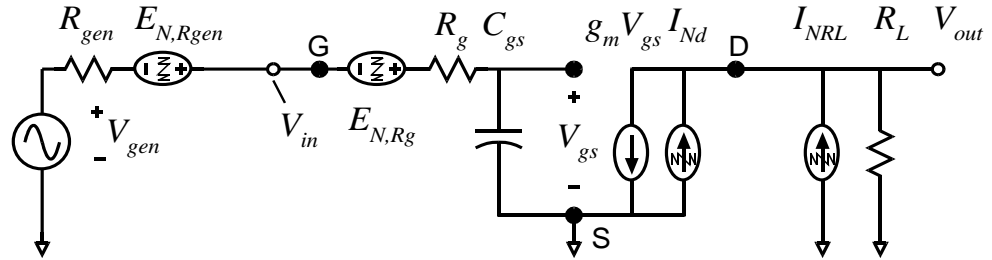
Simple amplifier, with simplified noise model.

Notation: Single - sided, Hz - based spectral densities

$$\tilde{S}_{V_n V_n} = 4kTR \text{ or } \tilde{S}_{I_n I_n} = 4kTG \text{ for all resistors}$$

$$\tilde{S}_{I_{nd} I_{nd}} = 4kTg_m \text{ for the FET channel noise.}$$

# Circuit Noise Analysis: 1st Example (b)



Now calculate the output voltage :

$$\begin{aligned}
 V_{out} &= \left( V_{gen} + E_{N,R_{gen}} + E_{N,R_g} \right) \left( 1 + j2\pi f C_{gs} (R_g + R_{gen}) \right)^{-1} (-g_m R_L) \\
 &\quad + \left( I_{N,d} + I_{N,R_L} \right) R_L \\
 &= V_{out,signal} + V_{out,amp\_noise} + V_{out,gen\_noise}
 \end{aligned}$$

$$V_{out,signal} = V_{gen} \left( 1 + j2\pi f C_{gs} (R_g + R_{gen}) \right)^{-1} (-g_m R_L)$$

$$V_{out,amp\_noise} = E_{N,R_g} \left( 1 + j2\pi f C_{gs} (R_g + R_{gen}) \right)^{-1} (-g_m R_L) + \left( I_{N,d} + I_{N,R_L} \right) R_L$$

$$V_{out,gen\_noise} = E_{N,R_{gen}} \left( 1 + j2\pi f C_{gs} (R_g + R_{gen}) \right)^{-1} (-g_m R_L)$$

where

$$\tilde{S}_{V_n V_n}(jf) = 4kTR \text{ or } \tilde{S}_{I_n I_n}(jf) = 4kTG \text{ for all resistors}$$

$$\tilde{S}_{I_{nd} I_{nd}}(jf) = 4kT\Gamma g_m \text{ for the FET channel noise.}$$

# Reminder

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If

$$V_y(jf) = H(jf)V_x(jf)$$

Then

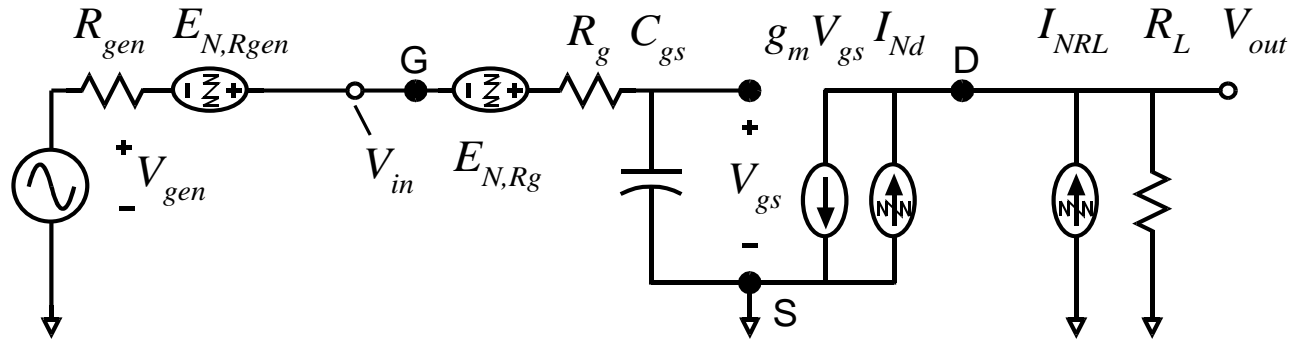
$$\tilde{S}_{V_y V_x}(jf) = H(jf)\tilde{S}_{V_y V_x}(jf)$$

$$\tilde{S}_{V_x V_y}(jf) = \tilde{S}_{V_x V_y}(jf)H^*(jf)$$

and

$$\tilde{S}_{V_y V_y}(jf) = \|H(jf)\|^2 \tilde{S}_{V_x V_x}(jf)$$

# Circuit Noise Analysis: 1st Example (c)



So :

$$V_{\text{out;signal}} = V_{\text{gen}} \left( 1 + j2\pi f C_{gs} (R_g + R_{gen}) \right)^{-1} (-g_m R_L)$$

$$\tilde{S}_{V_{amp,out}}(jf) = \tilde{S}_{N,R_g} \frac{(g_m R_L)^2}{1 + (2\pi f C_{gs})^2 (R_g + R_{gen})^2} + (\tilde{S}_{I_{N,d}} + \tilde{S}_{I_{N,R_L}}) (R_L)^2$$

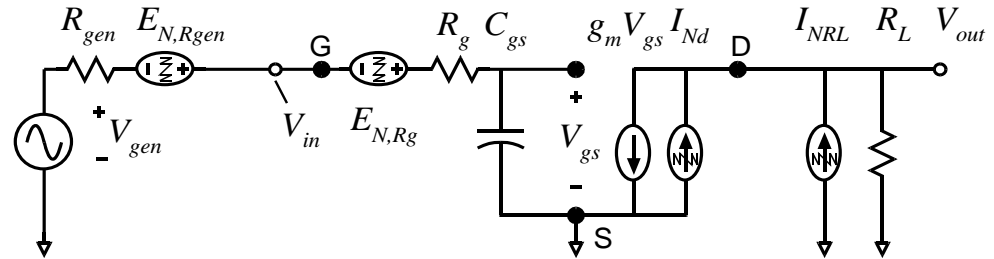
$$\tilde{S}_{V_{gen,out}}(jf) = \tilde{S}_{N,R_{gen}} \frac{(g_m R_L)^2}{1 + (2\pi f C_{gs})^2 (R_g + R_{gen})^2}$$

where

$$\tilde{S}_{V_n V_n}(jf) = 4kTR \text{ or } \tilde{S}_{I_n I_n}(jf) = 4kTG \text{ for all resistors}$$

$$\tilde{S}_{I_{nd} I_{nd}}(jf) = 4kT\Gamma g_m \text{ for the FET channel noise.}$$

# Circuit Noise Analysis: 1st Example (d)



The outputsignal

$$V_{\text{out,signal}} = V_{\text{gen}} \left( 1 + j2\pi f C_{gs} (R_g + R_{gen}) \right)^{-1} (-g_m R_L)$$

$$= A_v(j2\pi f) V_{\text{gen}}$$

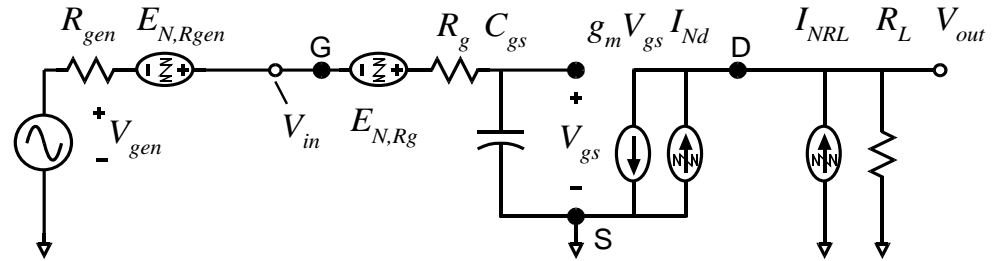
The outputnoise \* due to the amplifier \*

$$\tilde{S}_{V_{\text{amp,out}}}(jf) = 4kTR_g \frac{(g_m R_L)^2}{1 + (2\pi f C_{gs})^2 (R_g + R_{gen})^2} + \left( 4kT \Pi g_m + \frac{4kT}{R_L} \right) (R_L)^2$$

The outputnoise \* due to the generator \*

$$\tilde{S}_{V_{\text{gen,out}}}(jf) = 4kTR_{gen} \frac{(g_m R_L)^2}{1 + (2\pi f C_{gs})^2 (R_g + R_{gen})^2}$$

# Circuit Noise Analysis: 1st Example (e)



Now Define \*equivalent input noise\*

$$V_{out} = A_v(jf) * V_{gen} + V_{out,amp\_noise} + V_{out,gen\_noise}$$

$$= A_v(jf) * (V_{gen} + V_{in,amp\_noise} + V_{in,gen\_noise})$$

This means simply:  $V_{in,gen\_noise} = E_{N,gen}$  and  $V_{in,amp\_noise} = V_{out,amp\_noise} / A_v(jf)$

So the amplifier input-referred noise is :

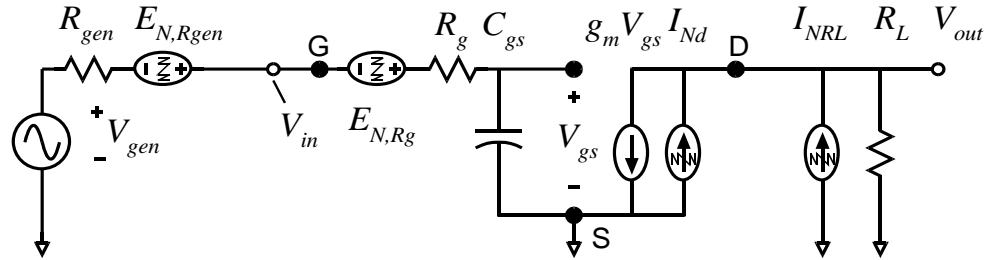
$$\tilde{S}_{V_{amp,in}}(jf) = \frac{\tilde{S}_{V_{amp,out}}(jf)}{\|A_v(jf)\|^2} = \tilde{S}_{V_{amp,out}}(jf) \cdot \frac{1 + (2\pi f C_{gs})^2 (R_g + R_{gen})^2}{(g_m R_L)^2}$$

And the input noise \* due to the generator \* is :

$$\tilde{S}_{V_{gen,in}}(jf) = 4kTR_{gen}$$



# Circuit Noise Analysis: 1st Example (f)



$$\tilde{S}_{V_{amp,in}}(jf) = 4kTR_g \text{ input-referred noise from } R_g$$

$$+ 4kT\Gamma g_m \cdot \left(\frac{1}{g_m^2}\right)^2 \left(1 + (2\pi f C_{gs})^2 (R_g + R_{gen})^2\right)$$

input referred channel noise

$$+ \left(\frac{4kT}{R_L}\right) \left(\frac{1}{g_m^2}\right)^2 \left(1 + (2\pi f C_{gs})^2 (R_g + R_{gen})^2\right)$$

input-referred load resistor noise

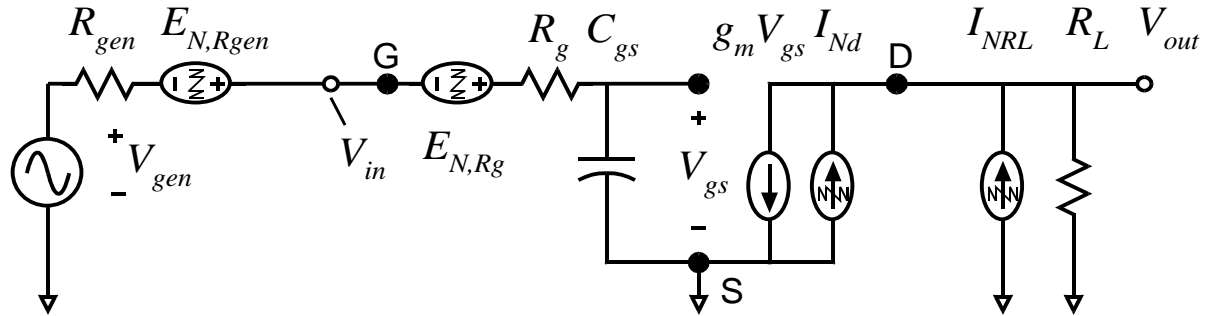
Input noise \* from the generator \*

$$\tilde{S}_{V_{gen,in}}(jf) = 4kTR_{gen}$$

# Circuit Noise Analysis: 1st Example (g)

Noise Figure definition :

$$F = \frac{\tilde{S}_{V_{gen,in}}(jf) + \tilde{S}_{V_{amp,in}}(jf)}{\tilde{S}_{V_{gen,in}}(jf)}$$



From which we can write

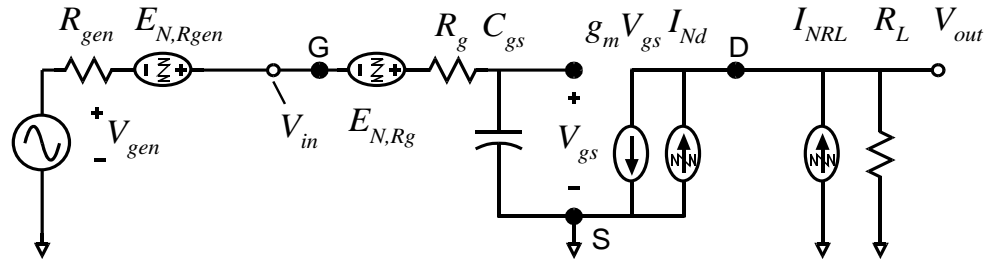
$$\tilde{S}_{V_{in,total\_noise}}(jf) = 4kTR_{gen}F$$

Signal/Noise ratio :

$$SNR = \frac{\tilde{S}_{V_{signal}}(jf)}{\tilde{S}_{V_{in,total\_noise}}(jf)}$$

Where  $\tilde{S}_{V_{signal}}(jf)$  is the input signal's power spectral density

# Circuit Noise Analysis: 1st Example: Summary



These are the exact steps for calculation of input-referred noise, output-referred noise, SNR, and noise figure.

This is how a computer might calculate these.

The method is extremely tedious, even for a small circuit.

Note that, in computing input-referred noise, many of our calculation steps were cancelled one we found the final answer.

Clearly, then, our method must be inefficient.

# Circuit Noise Analysis: 1st Example: Summary

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Analysis was hard because we

.....propagated the circuit noise generators to the circuit output,  
...then propagated them back to the input.

This involves cancelled steps - - - extra work.

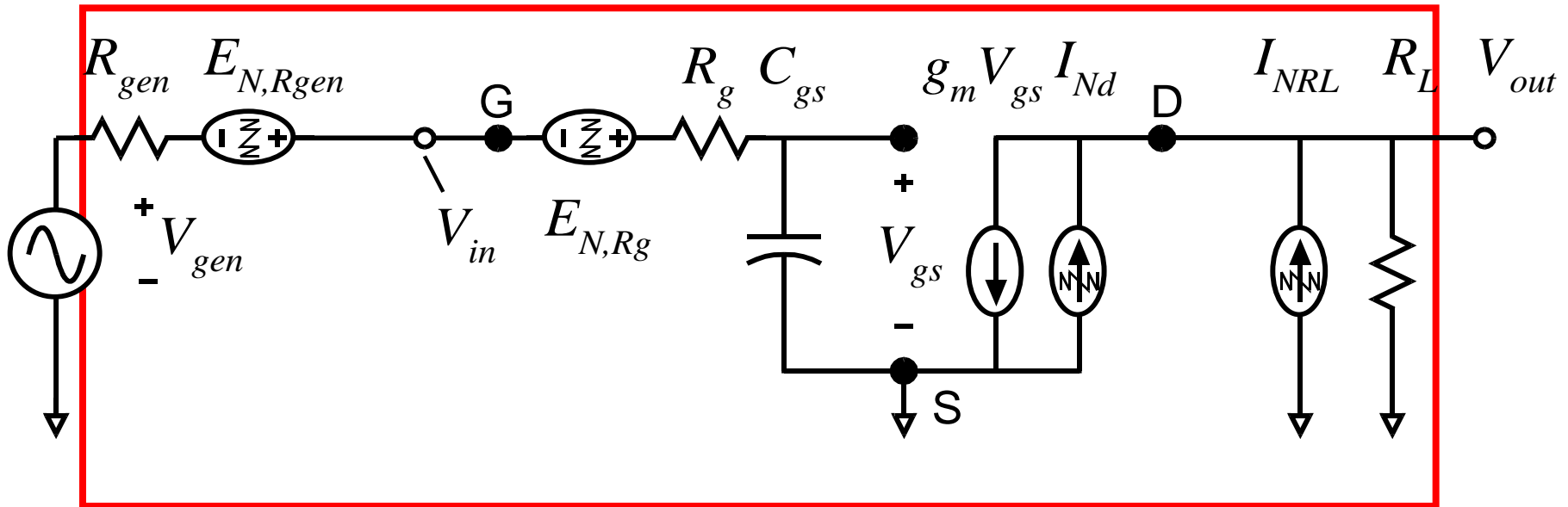
It is particularly inefficient because

\*\*\* The most important noise sources are near the input \*\*\*

# Circuit Noise Analysis: Source Transposition Method

Let us move all the circuit noise generators to the circuit input.

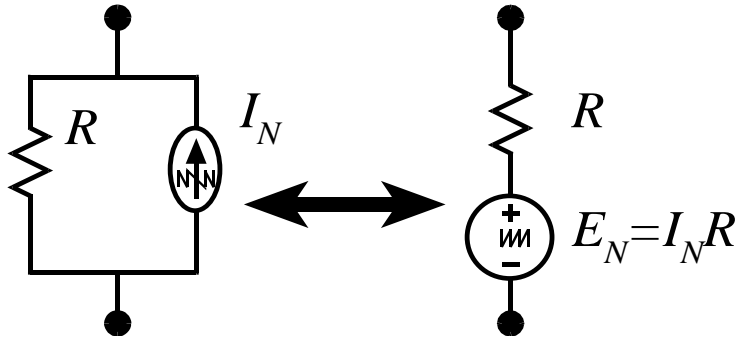
We must restrict ourselves to transformations which do not change the 2-port input-output characteristics of the network between input and output.



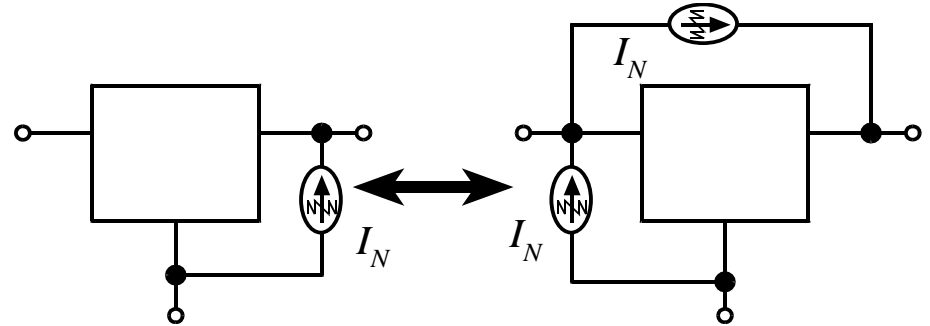
This means, make transformations only inside red box

# Circuit Noise Analysis: Source Transposition Method

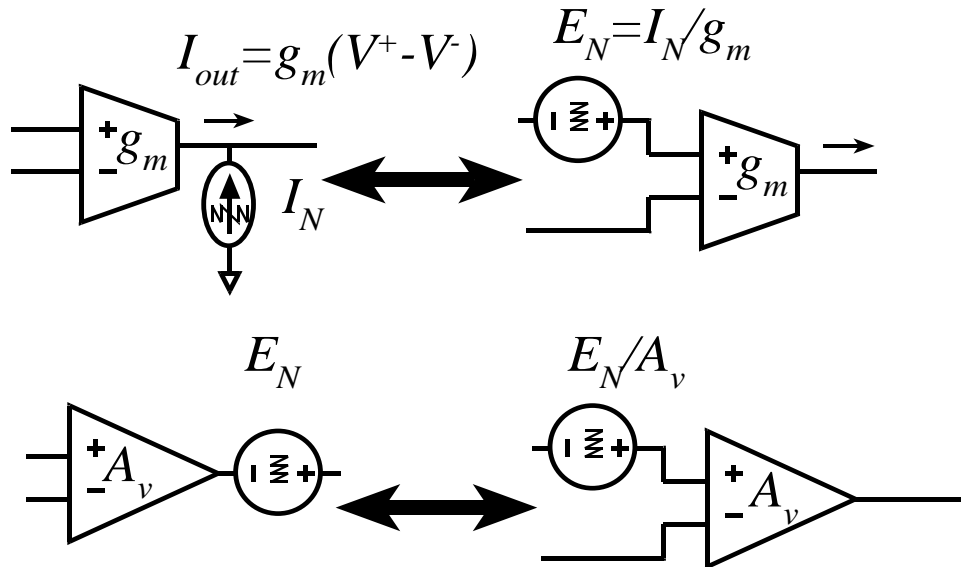
## Thevenin - Norton



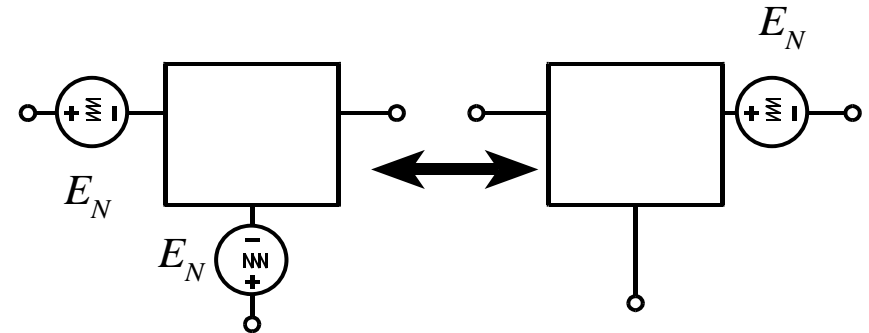
## Moving Current Across A Branch



## Output-Input

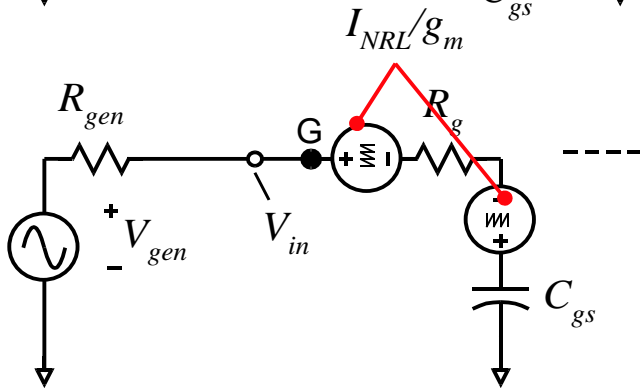
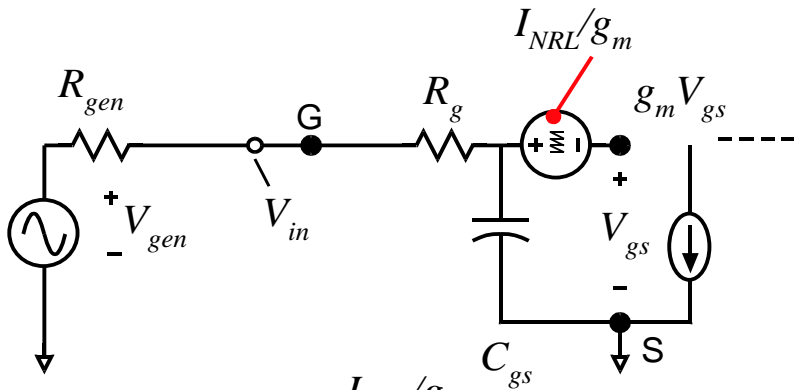
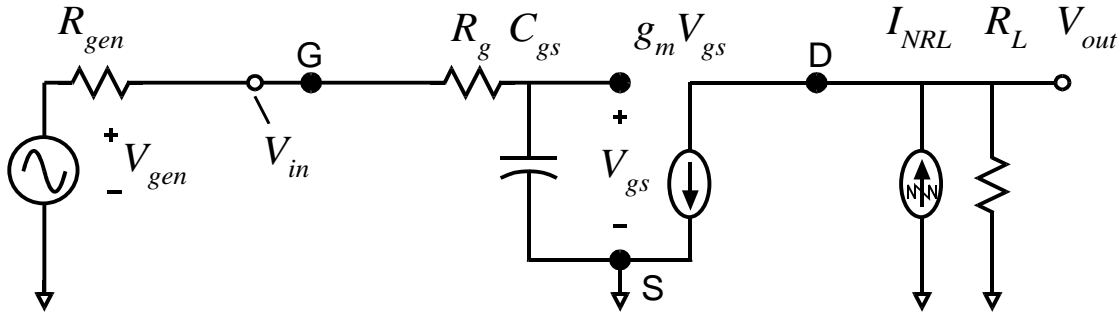


## Moving Voltage Through A Node

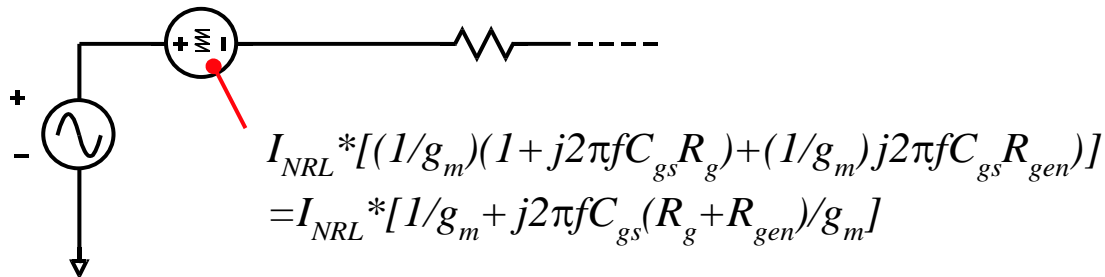
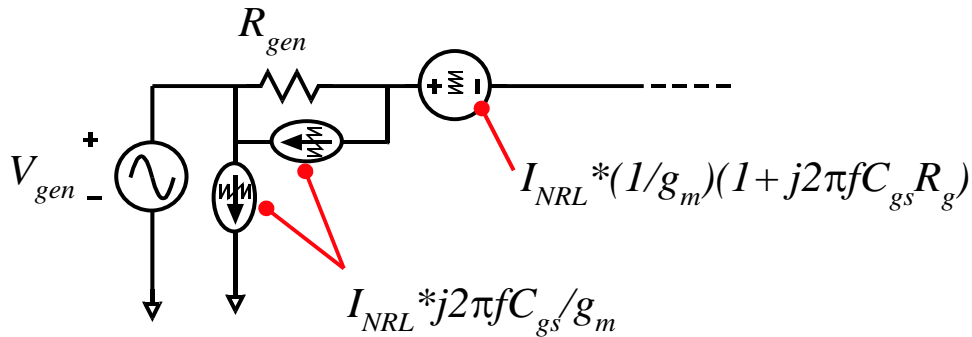
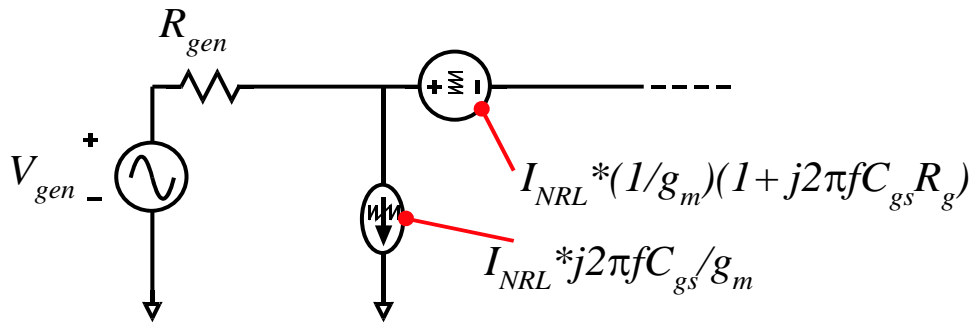


# Circuit Noise Analysis: Source Transposition Method

"Walk"  $I_{NRL}$  to the input



# Circuit Noise Analysis: Source Transposition Method





# Circuit Noise Analysis: Source Transposition Method

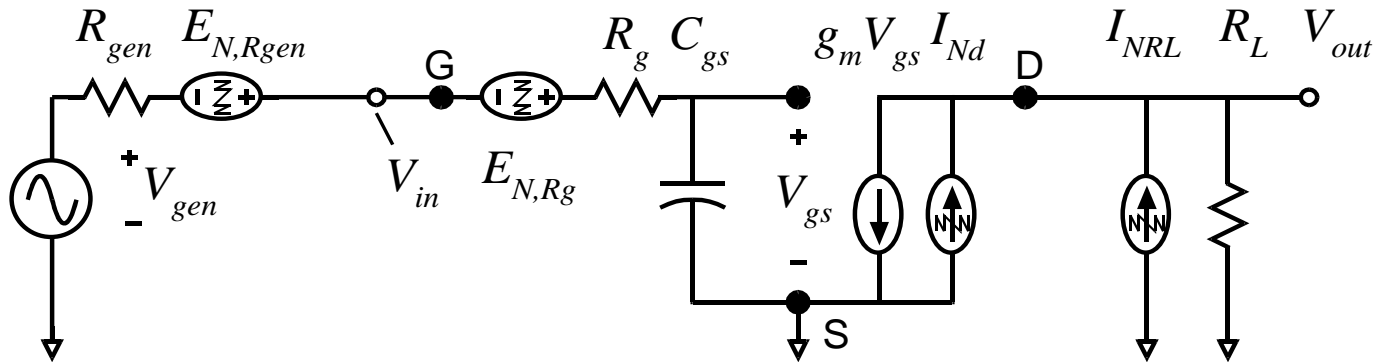
$$\tilde{S}_{V_{input};R_L noise}(jf) = \left( \frac{4kT}{R_L} \right) \left( \frac{1}{g_m^2} + \frac{(2\pi f C_{gs})^2 (R_g + R_{gen})^2}{g_m^2} \right)$$

This was certainly not an easy calculation, but because  $R_L$  is far from the input, it was the single hardest calculation to make.

The channel noise current generator is in parallel with that of  $R_L$  so,

$$\tilde{S}_{V_{input};channel\_noise}(jf) = (4kT \Gamma g_m) \left( \frac{1}{g_m^2} + \frac{(2\pi f C_{gs})^2 (R_g + R_{gen})^2}{g_m^2} \right)$$

# Circuit Noise Analysis: Source Transposition Method



In this particularly easy example, we can also see that

$$\tilde{S}_{V_{input};R_g}(jf) = 4kTR_g \quad \tilde{S}_{V_{input};generator}(jf) = 4kTR_{gen}$$

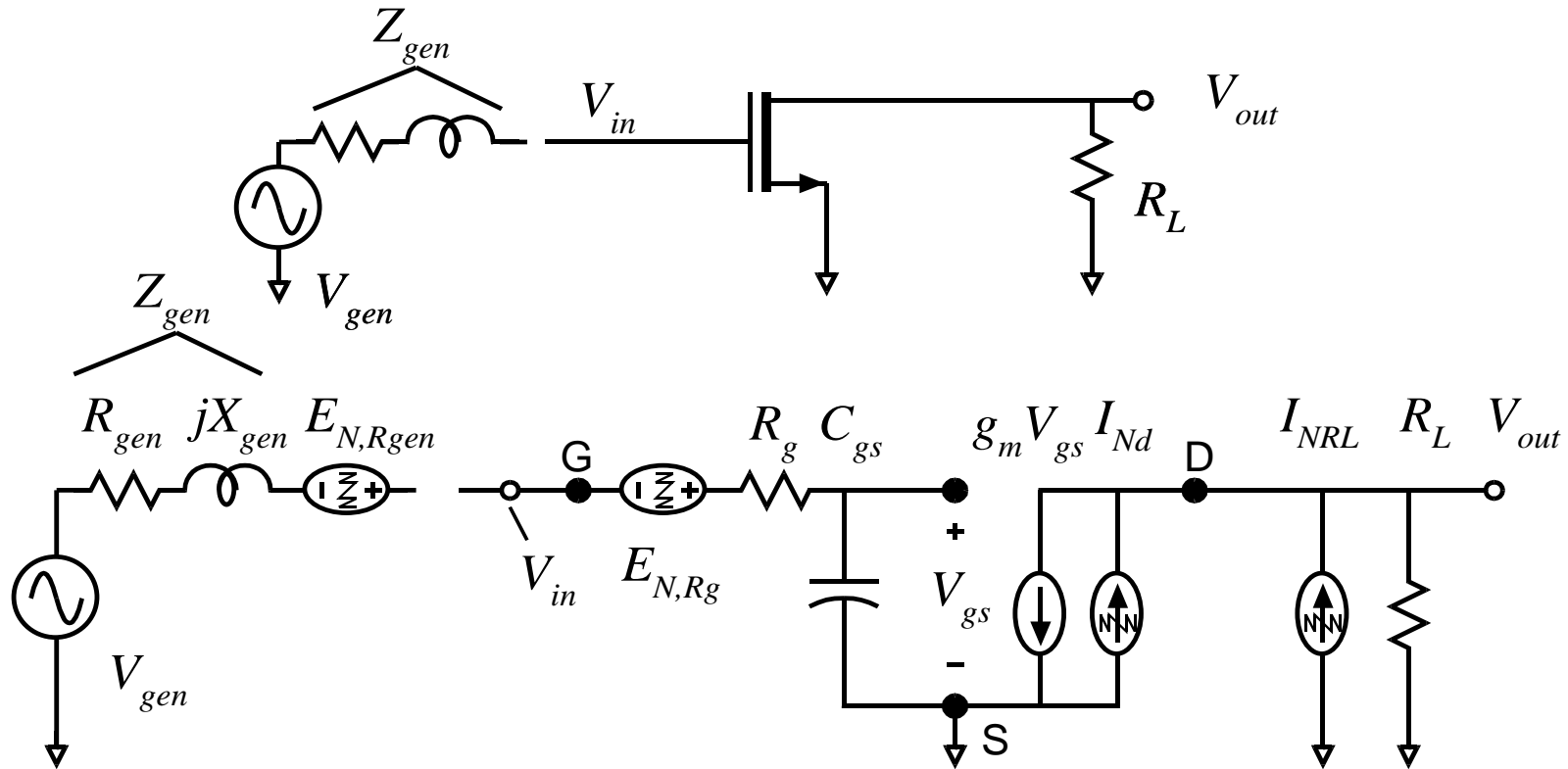
so

$$\tilde{S}_{V_{input};amplifier}(jf) = 4kTR_g + \left( 4kT\pi g_m + \frac{4kT}{R_L} \right) \left( \frac{1}{g_m^2} + \frac{(2\pi f C_{gs})^2 (R_g + R_{gen})^2}{g_m^2} \right)$$

hence

$$F = 1 + \frac{\tilde{S}_{V_{input};amplifier}}{\tilde{S}_{V_{input};generator}} = 1 + \frac{R_g}{R_{gen}} + \frac{1}{R_{gen}} \left( \frac{4kT\pi}{g_m} + \frac{4kT}{g_m^2 R_L} \right) \left( 1 + (2\pi f C_{gs})^2 (R_g + R_{gen})^2 \right)$$

# Input Noise Voltage / Input Noise Current Model

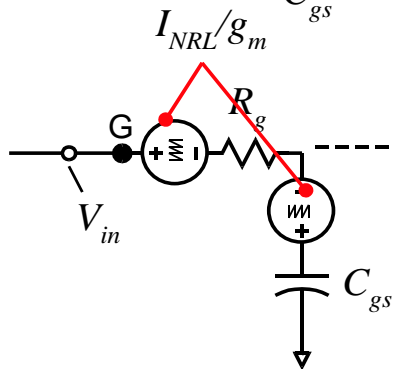
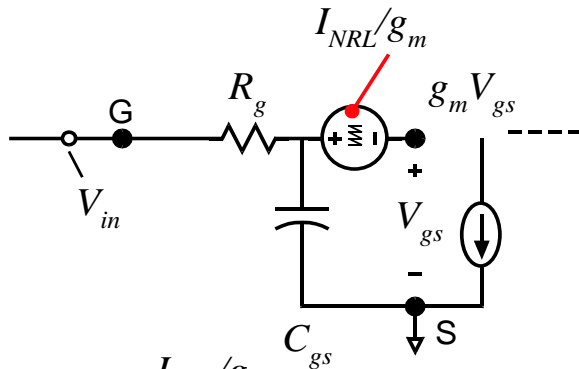
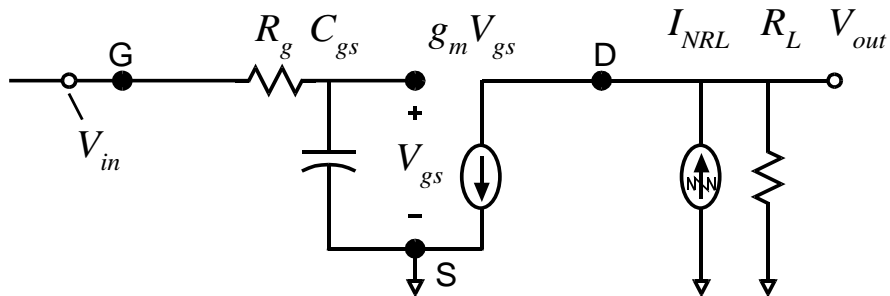


We frequently wish to specify noise of a device or circuit with the generator impedance unknown and unspecified

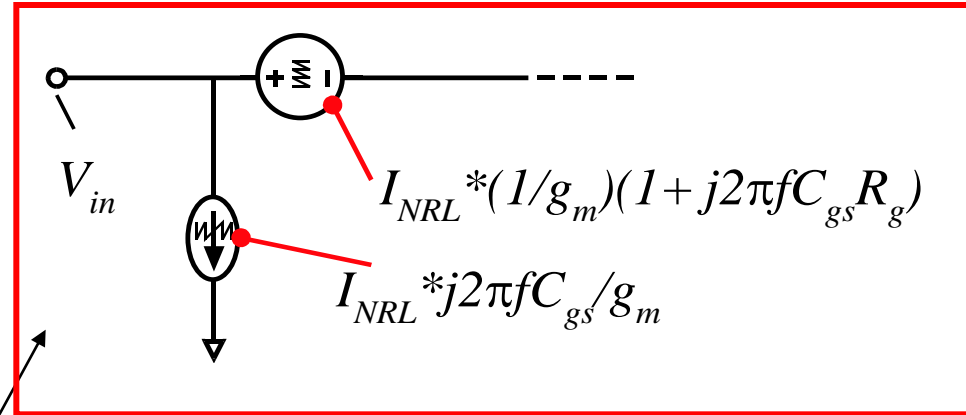
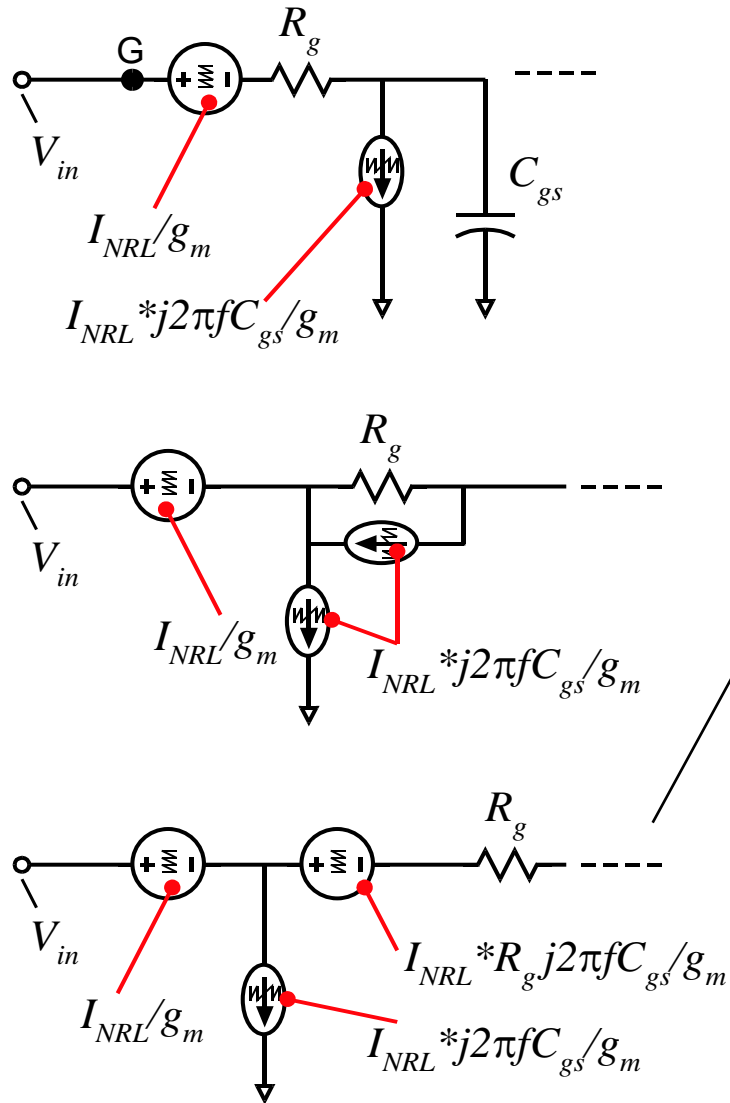
The  $E_n - I_n$  representation allows this.

# En-In Model: Source Transposition Again

Once again, "walk" sources to input - -but not into the generator  
 illustration of load resistor noise only.



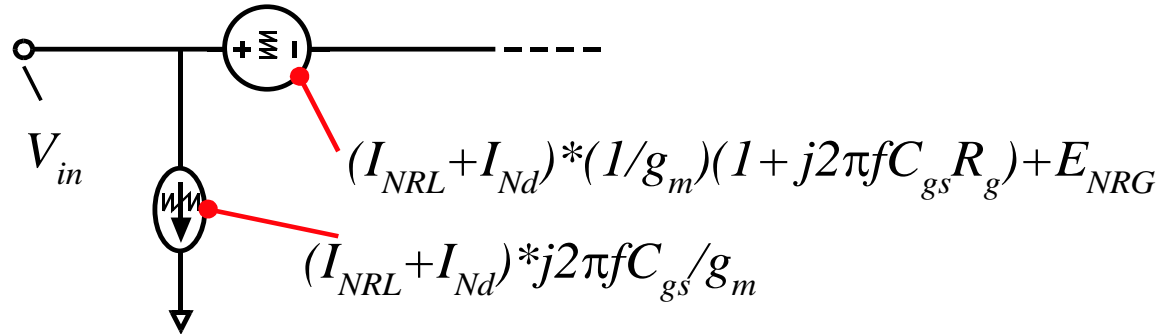
# En-In Model: Source Transposition Again



The output noise is represented at  $V_{in}$  by a combination of a voltage source and a current source.

As they are both related 1:1 to  $I_{NRL}$ , they are 100% correlated.

# En-In Model: With All Sources



Because

$$E_{n,total} = I_{NRL} \left( \frac{1}{g_m} \right) (1 + j2\pi f C_{gs} R_g) + I_{nd} \left( \frac{1}{g_m} \right) (1 + j2\pi f C_{gs} R_g) + E_{NRG}$$

$$I_{n,total} = I_{NRL} (j2\pi f C_{gs} / g_m) + I_{nd} (j2\pi f C_{gs} / g_m)$$

And Because  $\tilde{S}_{E_{NRG}}(jf) = 4kTR_g$   $\tilde{S}_{I_{NRL}}(jf) = 4kT / R_L$   $\tilde{S}_{I_{Nd}}(jf) = 4kT \Gamma g_m$

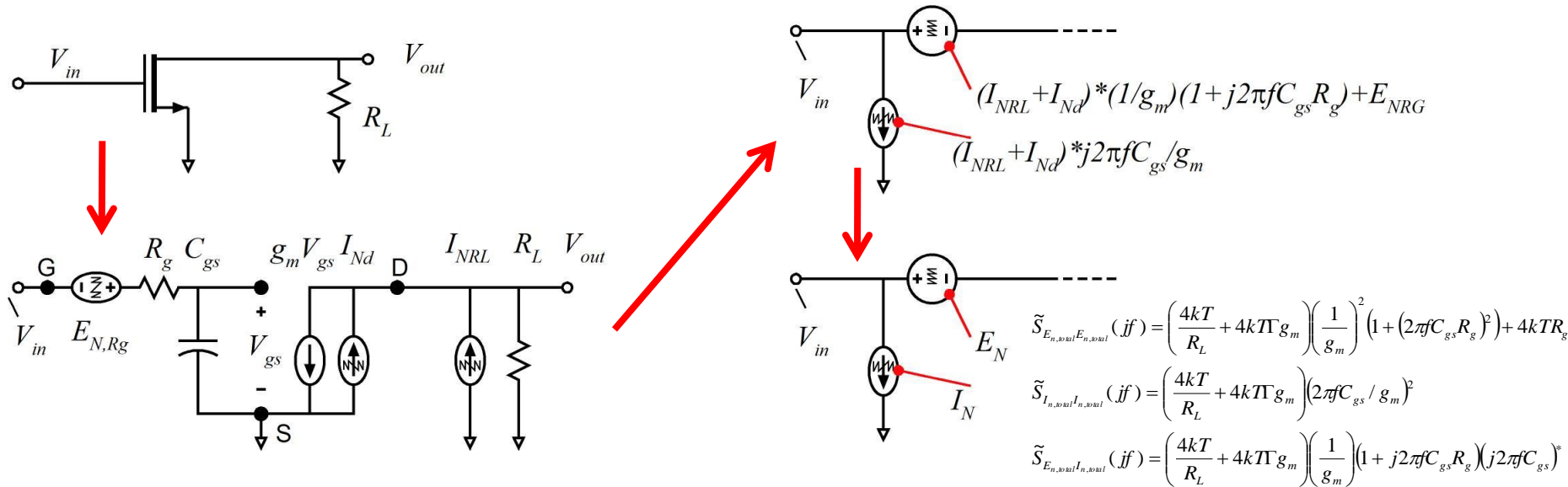
$$\tilde{S}_{E_{n,total} E_{n,total}}(jf) = \left( \frac{4kT}{R_L} + 4kT \Gamma g_m \right) \left( \frac{1}{g_m} \right)^2 (1 + (2\pi f C_{gs} R_g)^2) + 4kTR_g$$

$$\tilde{S}_{I_{n,total} I_{n,total}}(jf) = \left( \frac{4kT}{R_L} + 4kT \Gamma g_m \right) (2\pi f C_{gs} / g_m)^2$$

$$\tilde{S}_{E_{n,total} I_{n,total}}(jf) = \left( \frac{4kT}{R_L} + 4kT \Gamma g_m \right) \left( \frac{1}{g_m} \right) (1 + j2\pi f C_{gs} R_g) (j2\pi f C_{gs})^*$$

Note in particular the cross spectral density.

# En-In Model: With All Sources

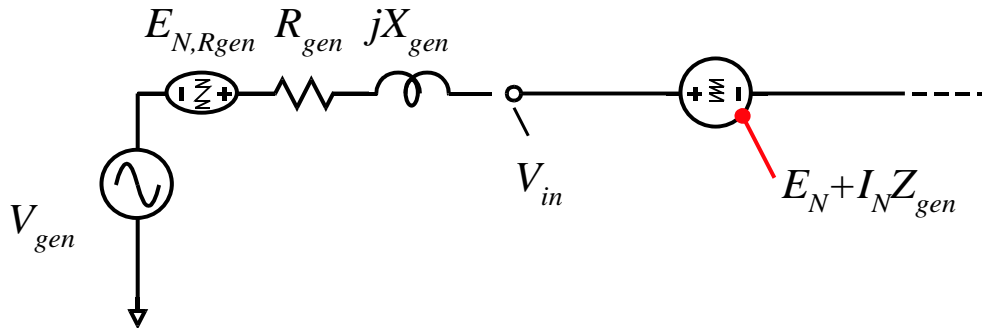
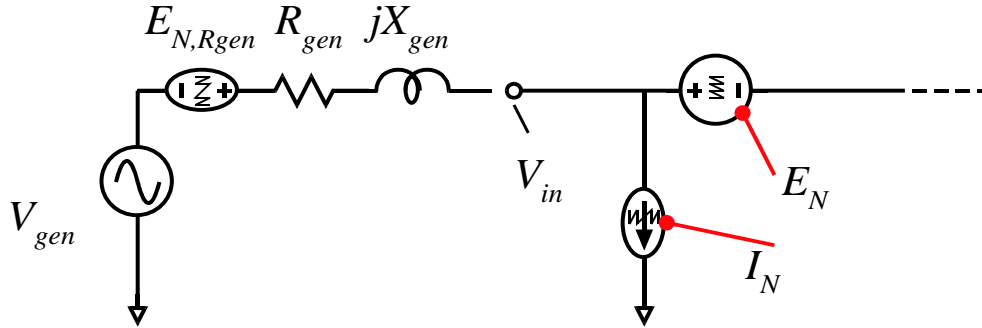


Consider what we have done :

An amplifier, with the generator not specified or present, is represented by a pair of correlated noise generators at its input.

Later, when a generator impedance is specified,  $\tilde{S}_{E_n}$ ,  $\tilde{S}_{I_n}$ , and  $\tilde{S}_{E_n I_n}$  can be used to calculate the total input noise (voltage, current, or available power).

# Using the En-In Model to Compute total Noise



Given a circuit with specified  $\tilde{S}_{E_n, total E_n, total}(jf)$ ,  $\tilde{S}_{I_n, total I_n, total}(jf)$ , and  $\tilde{S}_{E_n, total I_n, total}(jf)$ , and given a specified generator impedance  $Z_{gen} = R_{gen} + jX_{gen}$

$$E_{n, total, amplifier} = E_n + I_N Z_g$$

So

$$\begin{aligned} \tilde{S}_{E_n, total, amplifier} &= \tilde{S}_{E_n} + \|Z_g\|^2 \tilde{S}_{I_n} + 2 \operatorname{Re}\{\tilde{S}_{E_n I_n} Z_g^*\} \\ &= \tilde{S}_{E_n} + \|Z_g\|^2 \tilde{S}_{I_n} + 2 \operatorname{Re}\{\tilde{S}_{E_n I_n} (R_{gen} - jX_{gen})\} \end{aligned}$$



# Using the En-In Model--Conclusion

If we use the circuit relationship

$$\begin{aligned}\tilde{S}_{E_n, total, amplifier} &= \tilde{S}_{E_n} + \|Z_g\|^2 \tilde{S}_{I_n} + 2 \operatorname{Re}\{\tilde{S}_{E_n I_n} Z_g^*\} \\ &= \tilde{S}_{E_n} + \|Z_g\|^2 \tilde{S}_{I_n} + 2 \operatorname{Re}\{\tilde{S}_{E_n I_n} (R_{gen} - jX_{gen})\}\end{aligned}$$

and the device relationships

$$\tilde{S}_{E_n, total E_n, total}(jf) = \left( \frac{4kT}{R_L} + 4kT\Gamma g_m \right) \left( \frac{1}{g_m} \right)^2 \left( 1 + (2\pi f C_{gs} R_g)^2 \right) + 4kT R_g$$

$$\tilde{S}_{I_n, total I_n, total}(jf) = \left( \frac{4kT}{R_L} + 4kT\Gamma g_m \right) (2\pi f C_{gs} / g_m)^2$$

$$\tilde{S}_{E_n, total I_n, total}(jf) = \left( \frac{4kT}{R_L} + 4kT\Gamma g_m \right) \left( \frac{1}{g_m} \right) \left( 1 + j2\pi f C_{gs} R_g \right) (j2\pi f C_{gs})^*$$

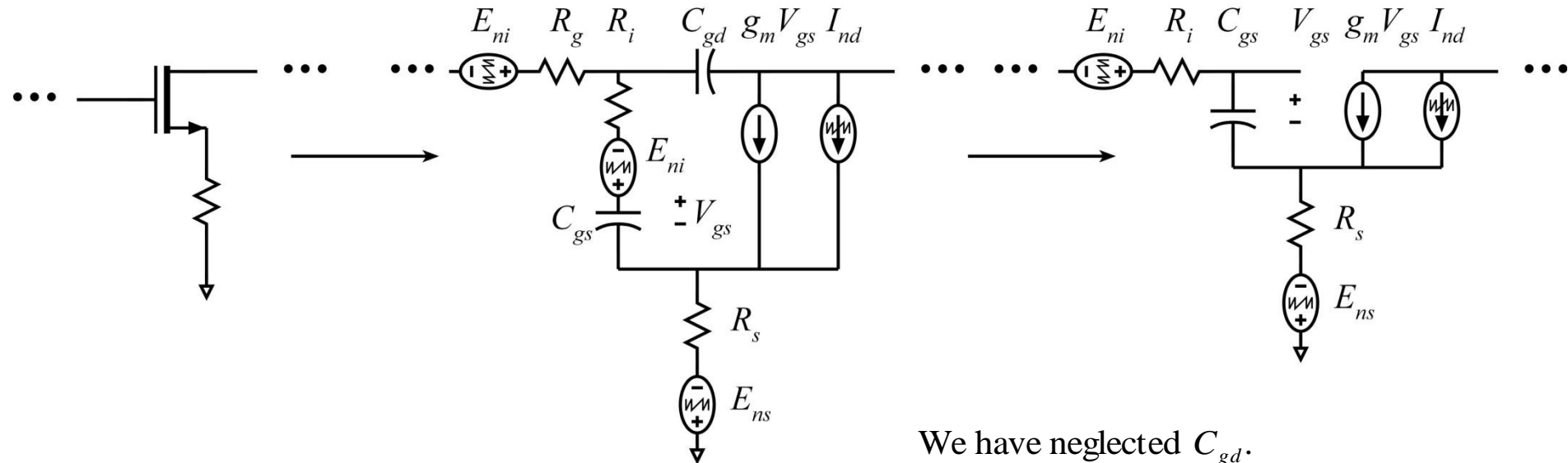
Then by varying  $Z_g$  (calculus), we can find the device minimum noise figure and the optimum source impedance which provides this, i.e. we can calculate the Fukui FET noise figure expression.

**Supplementary slides follow**

# Example Problem (1a): FET with Source Degeneration

Circuit

Equivalent Circuit

Simplified  
Equivalent Circuit

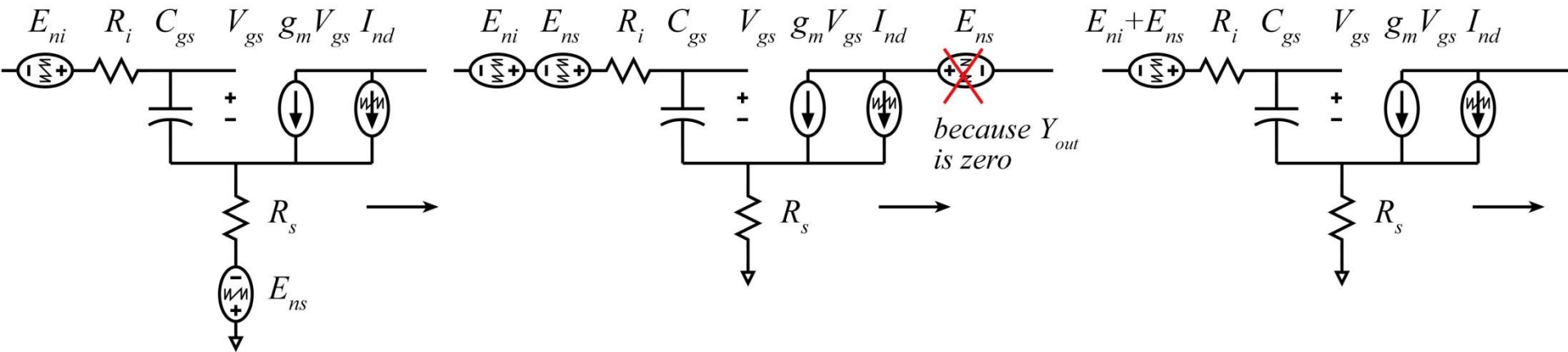
We have neglected  $C_{gd}$ .

...approximation introduces some error.

We have lumped together  $R_g$  and  $R_i$ .

...no approximation, no error.

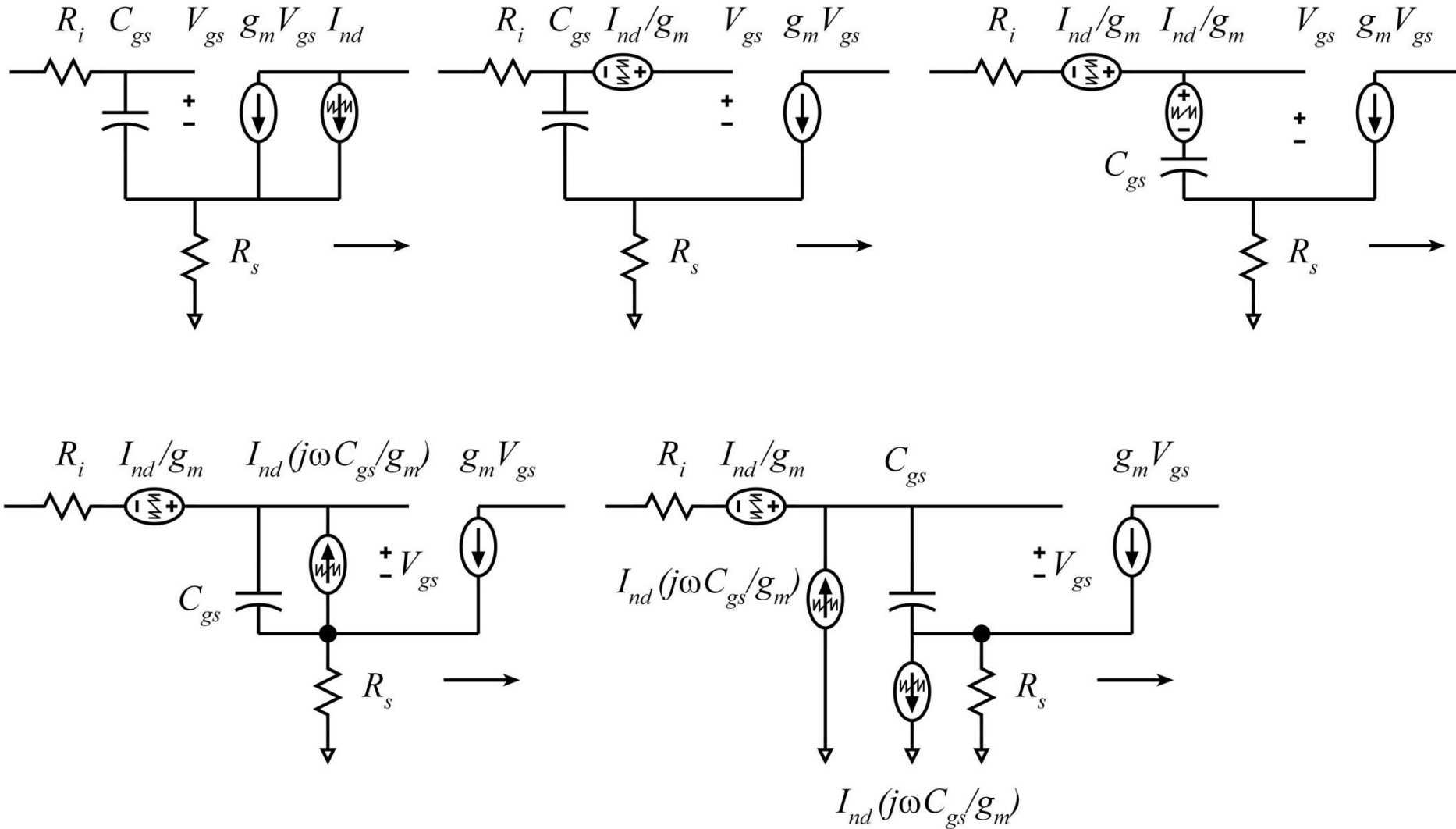
# Example Problem (1b): FET with Source Degeneration



We have moved the noise generators associated with  $R_s$  and  $R_g$  to the input.

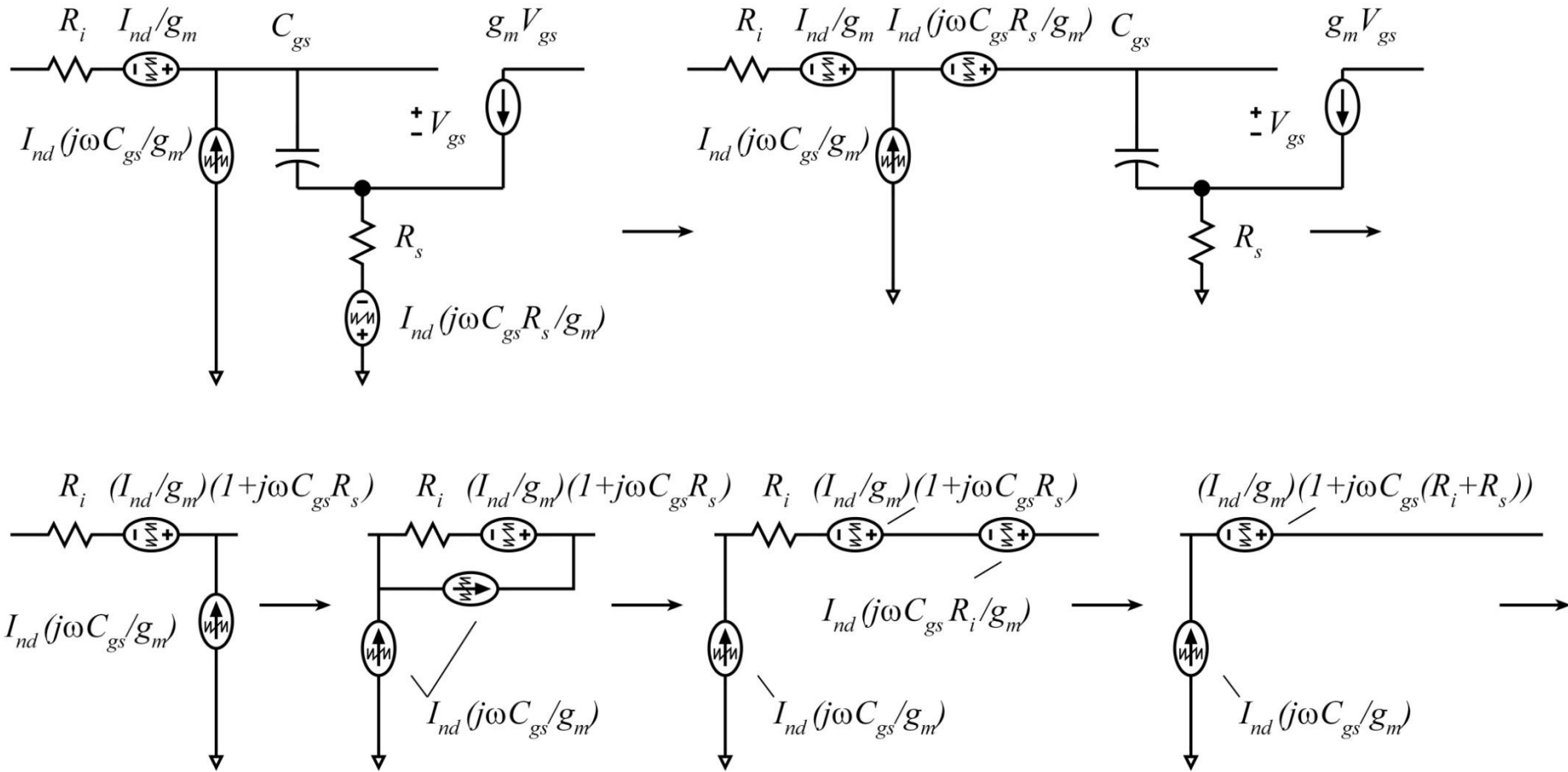
Next slide --- concentrate on  $I_{nd}$  alone.

# Example Problem (1c): FET with Source Degeneration



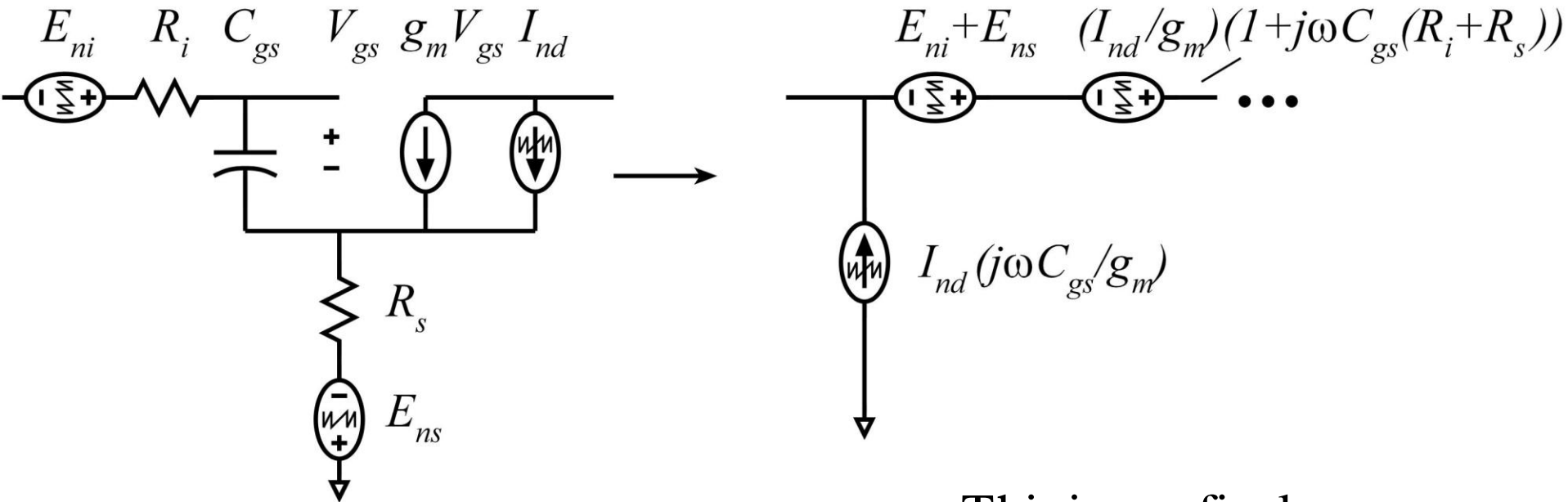
Recall : we must later replace  $R_i$  and  $R_s$  noise generators.

# Example Problem (1d): FET with Source Degeneration



Recall : we must later replace  $R_i$  and  $R_s$  noise generators.

# Example Problem (1f): FET with Source Degeneration



This is our final answer

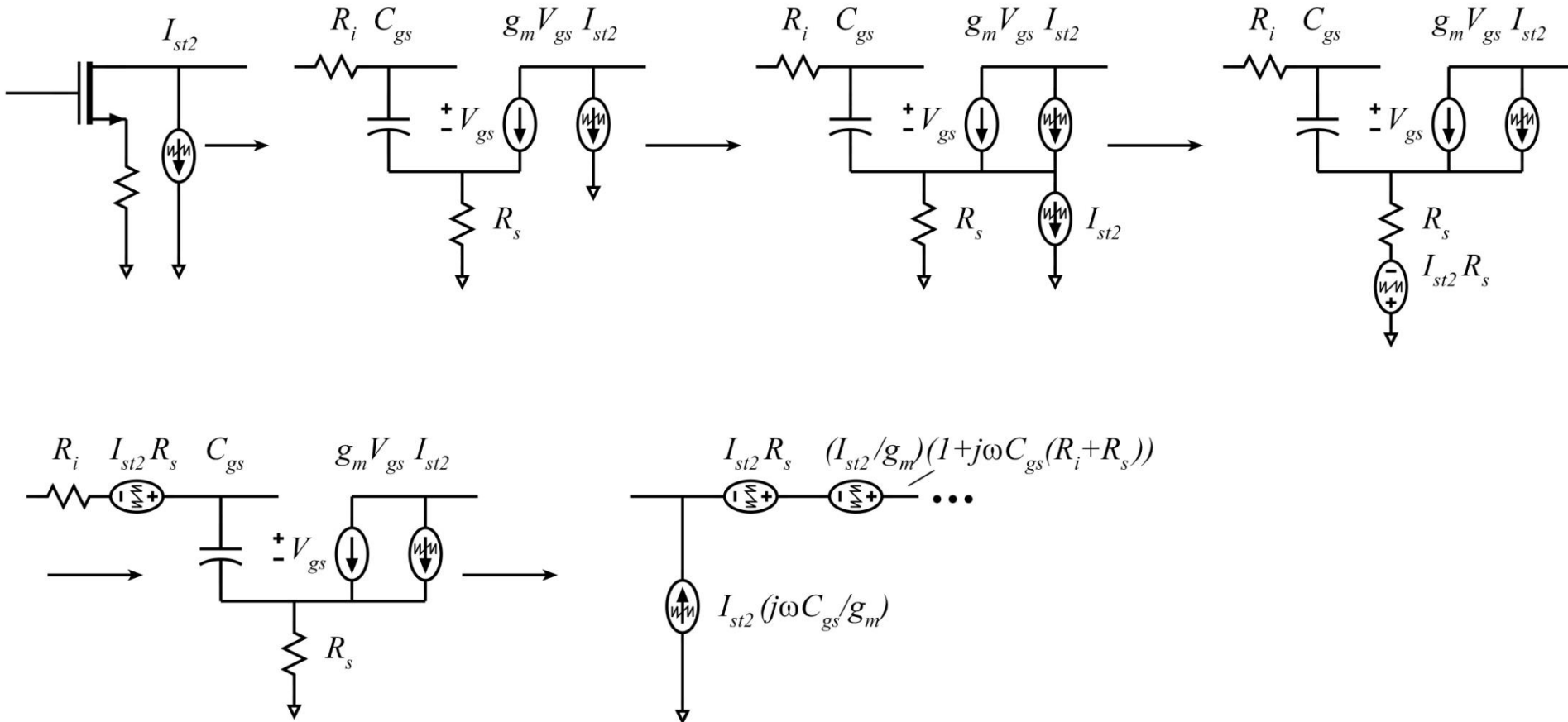
Recall that :

$$\tilde{S}_{E_{ni}} = 4kTR_i$$

$$\tilde{S}_{E_{ns}} = 4kTR_s$$

$$\tilde{S}_{I_{nd}} = 4kT\Gamma g_m$$

# Example Problem (1g): FET with Source Degeneration



We can now use the result of the previous page to find the input-referred noise resulting from the 2nd-stage input-referred noise current  $I_{st2}$ .